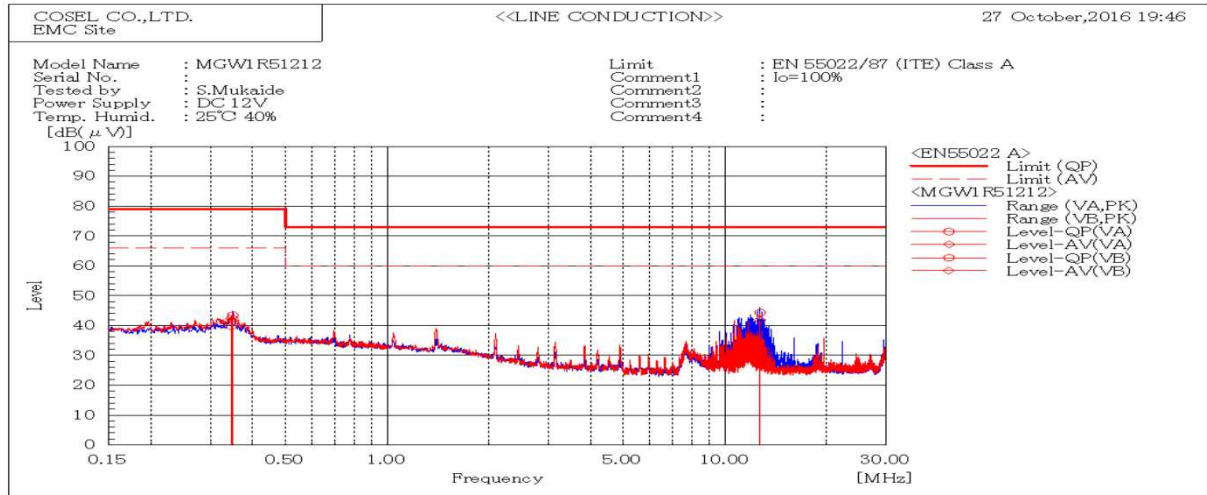
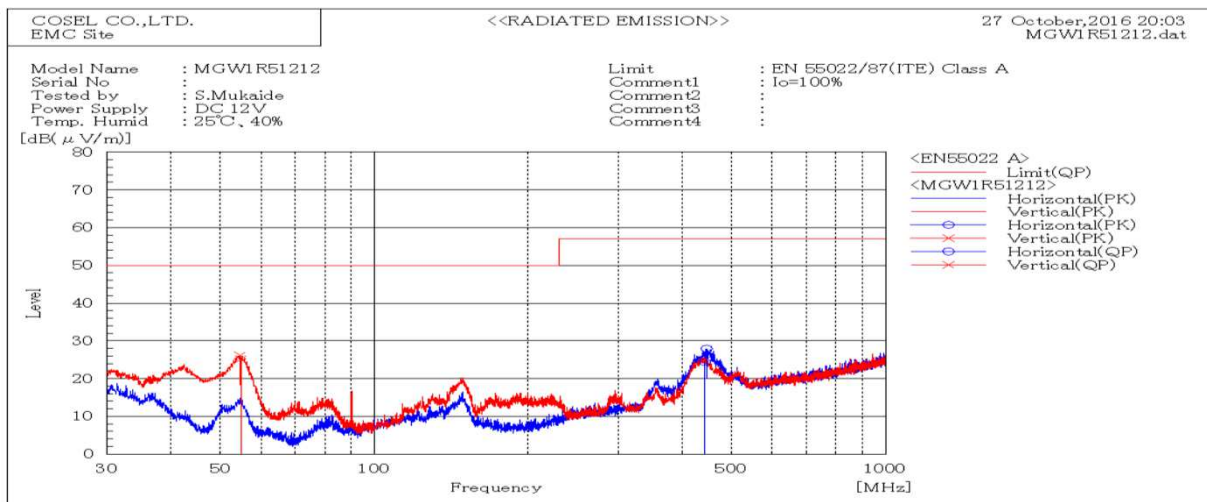


DATA SHEET		Date	28-Oct-16
Model	MGW1R51212	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide



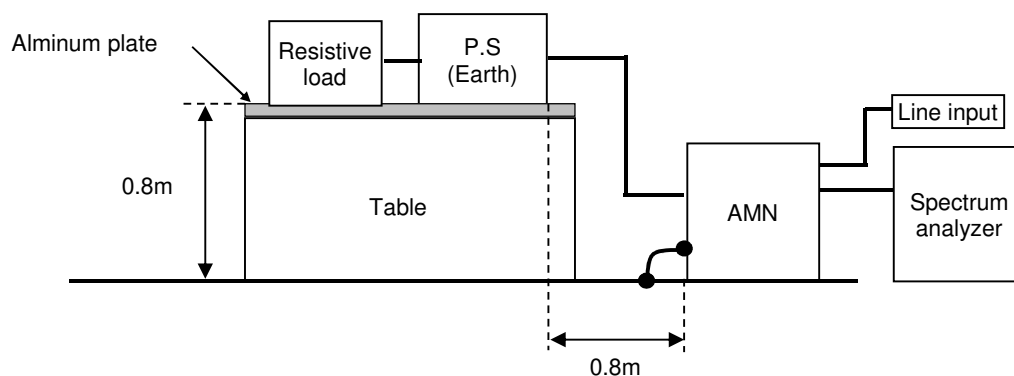
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.34965	VB	43.5	41.2	79	66	35.5	24.8	Pass	
0.34639	VA	42.3	39.5	79	66	36.7	26.5	Pass	
12.69725	VA	44.3	41.8	73	60	28.7	18.2	Pass	



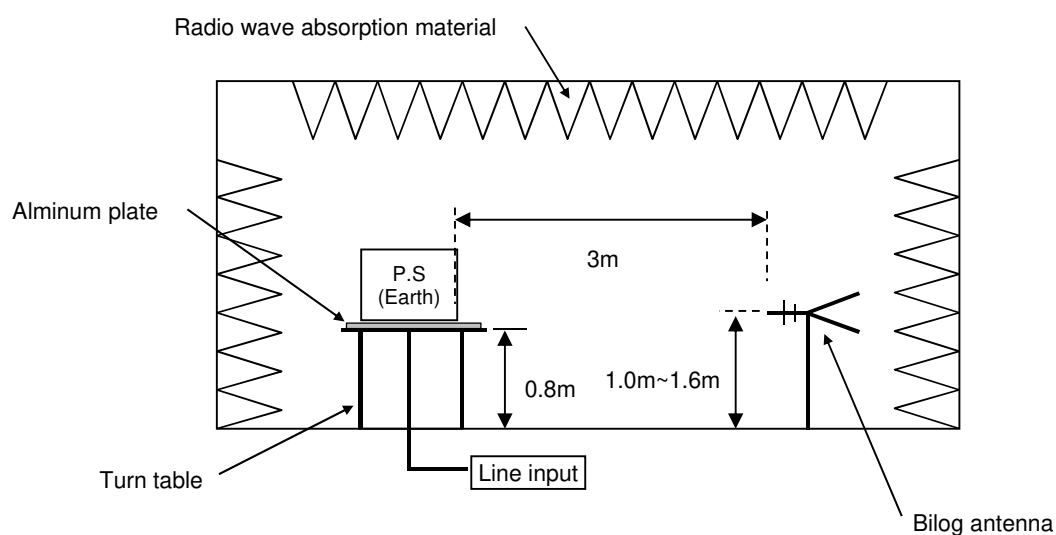
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
54.766	V	Stable	25.1	50.0	24.9	Pass	103	349	
443.304	H	Stable	24.4	57.0	32.6	Pass	122	329	

DATA SHEET		Date	28-Oct-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide

1. Line conduction



2. Radiated emission

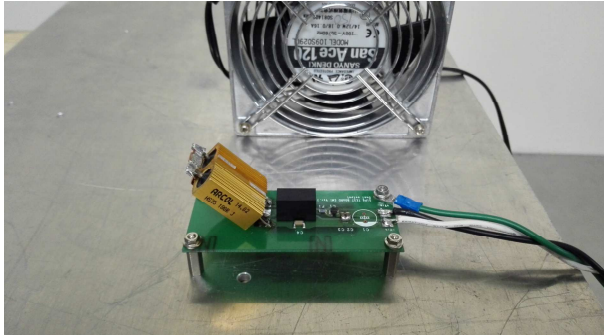


Conditions

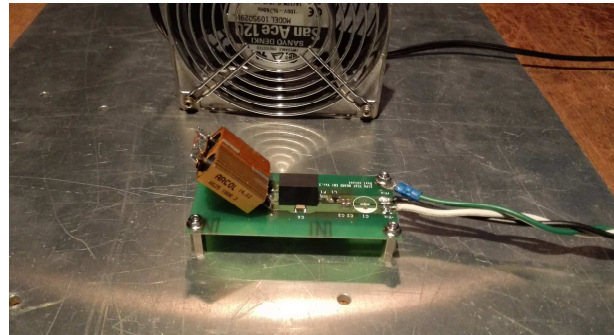
Test : EMI
Model Name : MGW1R5□□

○Photographs of Test Set-Up

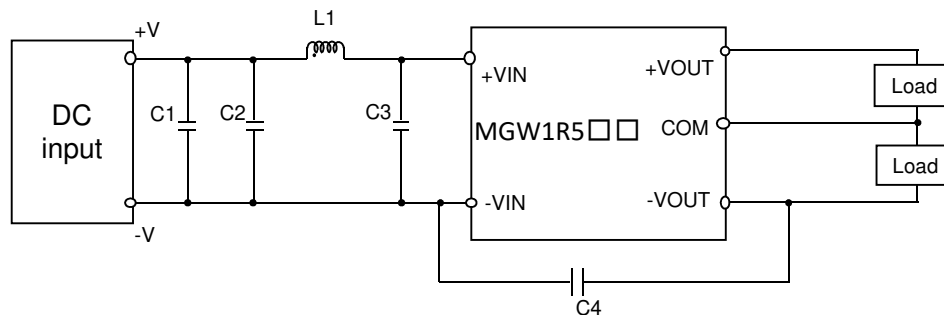
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry



C1,C2,C3 : MGS1R505□□ 16V 22 μ F Ceramic capacitor (GRM31CR71C226K MURATA MANUFACTURING)
MGS1R512□□ 25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
MGS1R524□□ 50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
MGS1R548□□ 100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)

C4 : MGS1R505□□ 2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING)
MGS1R512□□ 2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING)
MGS1R524□□ 2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING)
MGS1R548□□ 2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING)

L1 : MGS1R505□□ 1550mA 3.3 μ H Inductor(LQH32PN3R3NNCL MURATA MANUFACTURING)
MGS1R512□□ 1200mA 4.7 μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
MGS1R524□□ 900mA 10 μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
MGS1R548□□ 550mA 22 μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)